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Olympus LCPLN100XIR 100X NIR Objective

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Olympus LCPLN100XIR 100X NIR Objective

Stock **#90-484** NEW **1 In Stock**

C\$17,080.⁰⁰

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General

Model Number:
LCPLN100XIR

Compatible Tube Lens Focal Length (mm):
Focal Length: 180mm

Type:
Microscope Objective

Style:
Infinity Corrected

Manufacturer:

Physical & Mechanical Properties

0.22	Field of View (mm):
43.80	Length excluding Threads (mm):
31.00	Maximum Diameter (mm):
184	Weight (g):

Optical Properties

Compatible Cover Glass Thickness (mm): Glass: 0 - 0.7mm Silicon: 0 - 1.0mm	
1.80	Focal Length FL (mm):
100X	Magnification:
0.85	Numerical Aperture NA:
0.39	Resolving Power (μm):
0.38	Depth of Field (μm):
Working Distance (mm): Glass: 1.20 - 0.90mm Silicon: 1.20 - 1.05mm	
400 - 1600	Wavelength Range (nm):
22	Field Number (mm):
45	Parfocal Length (mm):
N/A	Immersion Liquid:
3.06	Entrance Pupil Diameter (mm):

Threading & Mounting

RMS / 20.32mm x 36 TPI	Mounting Threads:
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Regulatory Compliance

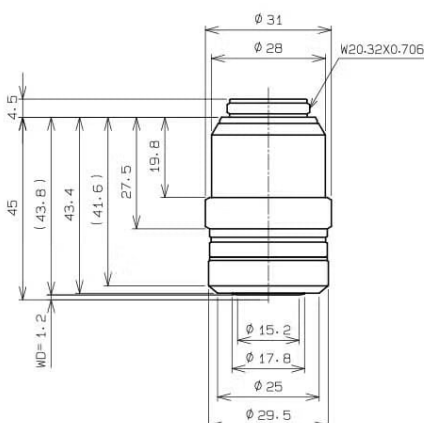
View	Certificate of Conformance:
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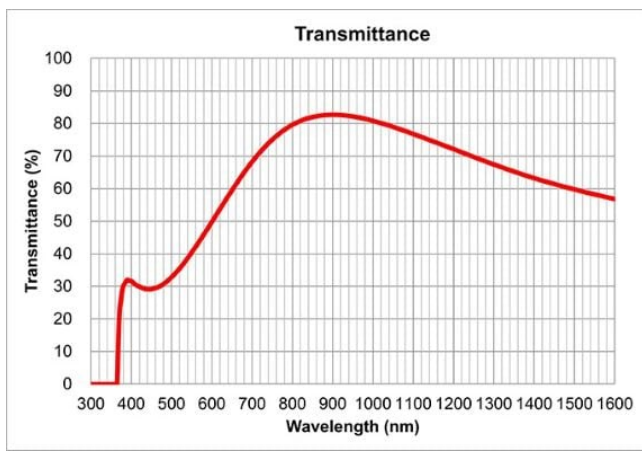
Product Details

- Long Working Distances to Reduce Risk of Specimen Damage
- Correction Collars to Adjust for Specimen Thickness
- Ideal for Silicon Wafer Inspection

Olympus Plan Achromatic Near-Infrared Objectives provide high transmission between 700 - 1600nm, making them an excellent choice for near-infrared microscopy when coupled with an NIR tube lens. These objectives feature long working distances to reduce the risk of damage to specimens and support up to field number 22 for observation. Magnifications of 20X and higher feature a correction collar to correct for aberrations based on the thickness of either the glass or silicon substrate being inspected. Olympus Plan Achromatic Near-Infrared Objectives are ideal for use in silicon wafer inspection to view the internal structure for defects.

Technical Information





LCPLN100XIR Transmission Graph

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